IEEE HOME I SEARCH IEEE I SHOP I WEB ACCOUNT I CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs	
IEEE )	Welcome United States Patent and Trademark Office  Welcome United States Patent and Trademark Office
Help FAQ Terms IEE	E Peer Review Quick Links Se.
Welcome to IEEE Xplore*	
O- Home O- What Can I Access? O- Log-out	Your search matched <b>493</b> of <b>1094442</b> documents.  A maximum of <b>500</b> results are displayed, <b>15</b> to a page, sorted by <b>Relevance Descending</b> order.
Tables of Contents	Refine This Search:
O- Journals	You may refine your search by editing the current search expression or enterinew one in the text box.
& Magazines	automatic and generation and random
O- Conference Proceedings	Check to search within this result set
O- Standards	Results Key:
Search	JNL = Journal or Magazine CNF = Conference STD = Standard
O- By Author O- Basic O- Advanced O- CrossRef	1 Automatic random variate generation for simulation input Hormann, W.; Leydold, J.; Simulation Conference Proceedings, 2000. Winter, Volume: 1, 10-13 Dec. 20 Pages: 675 - 682 vol.1
Member Services  O- Join IEEE	[Abstract] [PDF Full-Text (568 KB)] IEEE CNF
- Establish IEEE Web Account - Access the IEEE Member Digital Library	2 Automatic test generation using checkpoint encoding and antirando testing Yin, H.; Lebne-Dengel, Z.; Malaiya, Y.K.; PROCEEDINGS The Eighth International Symposium On Software Reliability Engineering, 2-5 Nov. 1997 Pages:84 - 95
O- Access the	[Abstract] [PDF Full-Text (832 KB)] IEEE CNF
IEEE Enterprise File Cabinet	3 Are random vectors useful in test generation?  Abramovici, M.; Miller, D.T.;  European Test Conference, 1989., Proceedings of the 1st, 12-14 April 1989  Pages: 22 - 25
	[Abstract] [PDF Full-Text (216 KB)] IEEE CNF
	4 Dynamic testability measures for ATPG

Ivanov, A.; Agarwal, V.K.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 7 , Issue: 5 , May 1988

Pages:598 - 608

[Abstract] [PDF Full-Text (1080 KB)] IEEE JNL

### 5 Automated synthesis of a multiple-sequence test generator using 2-**LFSR**

Xin Yuan; Chen, C.-I.H.;

ASIC Conference 1998. Proceedings. Eleventh Annual IEEE International, 13-Sept. 1998

Pages: 75 - 79

[Abstract] [PDF Full-Text (392 KB)] **IEEE CNF** 

#### 6 On using partial reset for pseudo-random testing

Soufi, M.; Savaria, Y.; Kaminska, B.;

Circuits and Systems, 1995. ISCAS '95., 1995 IEEE International Symposium on , Volume: 2 , 28 April-3 May 1995

Pages:949 - 952 vol.2

[Abstract] [PDF Full-Text (504 KB)] **IEEE CNF** 

# 7 Generating non-Gaussian random fields for sea surface simulations

Newsam, G.N.; Wegener, M.;

Acoustics, Speech, and Signal Processing, 1994. ICASSP-94., 1994 IEEE

International Conference on , Volume: vi , 19-22 April 1994

Pages:VI/195 - VI/198 vol.6

[Abstract] [PDF Full-Text (312 KB)] **IEEE CNF** 

#### 8 Weighted random test program generation for a per-pin tester

Gartner, J.; Driscoll, B.; Forlenza, D.; Forlenza, O.; Koprowski, T.; Lizambri, 1 Olsen, R.; Robertson, S.; Ryan, P.; Walter, A.;

Test Conference, 1990. Proceedings., International, 10-14 Sept. 1990 Pages:1000 - 1005

[Abstract] [PDF Full-Text (388 KB)] **IEEE CNF** 

## 9 A genetic approach to automatic bias generation for biased random instruction generation

Bose, M.; Jongshin Shin; Rudnick, E.M.; Dukes, T.; Abadir, M.;

Evolutionary Computation, 2001. Proceedings of the 2001 Congress on , Volum 1, 27-30 May 2001

Pages:442 - 448 vol. 1

[Abstract] [PDF Full-Text (584 KB)] IEEE CNF

#### 10 New approaches to the AGC non-conforming load problem

Douglas, L.D.; Green, T.A.; Kramer, R.A.;

Power Systems, IEEE Transactions on , Volume: 9 , Issue: 2 , May 1994

Pages:619 - 628

[Abstract] [PDF Full-Text (972 KB)] **IEEE JNL** 

### 11 TESTCHIP: a chip for weighted random pattern generation, evaluat and test control

Strole, A.P.; Wunderlich, H.-J.;

Solid-State Circuits, IEEE Journal of , Volume: 26 , Issue: 7 , July 1991 Pages: 1056 - 1063

[Abstract] [PDF Full-Text (720 KB)] **IEEE JNL** 

#### 12 An approach to software product testing

Munoz, C.U.;

Software Engineering, IEEE Transactions on , Volume: 14 , Issue: 11 , Nov. 1 Pages:1589 - 1596

[Abstract] [PDF Full-Text (724 KB)]

#### 13 Synchronizability of general periodic pattern signals

Stantchev, B.; Fettweis, G.;

Communications, 2000. ICC 2000. 2000 IEEE International Conference

on , Volume: 1 , 18-22 June 2000

Pages:336 - 340 vol.1

[Abstract] [PDF Full-Text (404 KB)]

### 14 Functional verification of the superscalar SH-4 microprocessor

Biswas, P.; Freeman, A.; Yamada, K.; Nakagawa, N.; Uchiyama, K.; Compcon '97. Proceedings, IEEE, 23-26 Feb. 1997

Pages:115 - 120

[Abstract] [PDF Full-Text (468 KB)] **IEEE CNF** 

#### 15 A new test pattern generation method for delay fault testing

Cremoux, S.; Fagot, C.; Girard, P.; Landrault, C.; Pravossoudovitch, S.; VLSI Test Symposium, 1996., Proceedings of 14th, 28 April-1 May 1996 Pages: 296 - 301

[Abstract] [PDF Full-Text (604 KB)]

<u>1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23</u> 25 26 27 28 29 30 31 32 33 Next

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved